

Search Notes

Application/Control No.

10/791,669

Examiner

John P. Sheehan

Applicant(s)/Patent under
Reexamination

SHIRAISHI ET AL.

Art Unit

1793

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| EAST | 3/21/2007 | JPS |
| EAST. Update | 11/20/2007 | JPS |
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